PCN Number: 202				200424001.1				PCN Date: Apr 28, 2020				
Title: Qualification of FFAB as an additional Fab Site option for select BICMOS13 devices								ces				
Customer Contact:			PCN Manager			Dept:			Quality Services			
					Estimated Sample				Date provided at			
Proposed 1 st Ship Date:			Jui	28, 202	20	Availability:			9	sample request.		
Change Type:												
	nbly Si	te			bly Pro				Assembly Materials			
	Design		$ \square$			cification	<u> </u>	Mechanical Specificatio			ication	
Test Site Wafer Bump Site		H			ping/Labeling Material			Test Process Wafer Bump Process				
			H		Fab Ma		\square	Wafer Fab Process				
	Wafer Fab Site		╎┝┤╴						Water rab Frocess			
	Part number change PCN Details											
Descripti	on of	Change:				Ctuns						
			d to a	nnounc	e the a	ualification	of its FF	AB f	abric	ation	facility a	s an
Texas Instruments is pleased to announce the qualification of its FFAB fabrication facility as an additional Wafer Fab source for the selected devices listed in "Product Affected" section.												
		Current Si	tes				Addi	ditional Sites				
Currer	nt	Process		Wafer		Additional		Process		Wafer		
Fab Si				Diam	eter	Fab Site				D	iameter	r
MAINEF	MAINEFAB BICMOS13		3	200	nm	FFAB BICMOS			S13	513 200mm		
Qual details are provided in the Qual Data Section. Reason for Change: Continuity of Supply												
		pact on For	m, F	it. Fun	ction.	Duality or	Reliabi	lity (posi	itive /	/ negativ	ve):
None			, .									
	to pro	duct ident	ificat	ion res	ultina	from this	PCN:					
Changeo			incat		arcing							
Current												
Chip S	Chip Site Chip Site		Drigin	(20L)	Chip S	Site Country	Code (21L)		Chip	Site Cit	у
MAINE	MAINEFAB CU		UA			USA				South Portland		ıd
New Fat												
Chip S	te Chip Site Or		Drigin	(20L)	Chip S	Site Country Code (2			_) Chip Site		Site Cit	у
FR-BIF	P-1	Т	ID			DEU				F	reising	
Sample product shipping label (not actual product label) TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL 2 /260C/1 YEAR SEAL DT OFT: ITEM: 39 LBL: 5A (L)T0:1750 (not actual product label) (1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) 20L) CS0: SHE (2L) ASO: MLA (2SL) ASO: MLA (2SL) ASO: MLA												
Product Affected Group:												
DS280DF810ABVR DS280DF810ABVT DS280DF810ABWR						D	S280E	DF810ABV	VT			

Qualification Report Approve Date 22-April-2020

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: DS280DF810ABWT	QBS Process Device: LMH1297RTVT R	QBS Process Reference LMX2581 SQENOPB	QBS Package Reference DS110DF1610SFB
ELFR	Early Life Failure Rate, Ta=115C, Tj∼160C	48HRS	-	-	3/2400/0	-
HTOL	Life Test, Ta=115C, Tj~160C	500HRS	-	-	3/231/0	-
HTOL	Life Test, Ta=125C	1000HRS	1/77/0	2/154/0	-	-
AC	Autoclave 121C	96HRS	-	-	3/231/0	-
HAST	Biased HAST, 130C/85%RH	96HRS	-	-	3/231/0	3/231/0
TC	Temperature Cycle, -55/125C	700CYC	-	-	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000HRS	-	-	3/231/0	3/231/0
HBM	ESD - HBM	2000V	1/3/0	-	3/9/0	-
CDM	ESD - CDM	1000V	1/3/0	-	-	-
LU	Latch-up	25C	1/6/0	-	3/18/0	-
LU	Latch-up	85C	1/60	-	3/18/0	-

- QBS: Qual By Similarity

- Qual Device DS280DF810ABWT is qualified at LEVEL3-260CG

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

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